


<b>Search Notes</b>  	<b>Application/Control No.</b>  10508846	<b>Applicant(s)/Patent Under Reexamination</b>  TOMOE ET AL.
	<b>Examiner</b>  Kiss, Eric B	<b>Art Unit</b>  2192

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
PALM Inventor search	08/09/2007	EBK
EAST (USPAT; US-PGPUB; FPRS; EPO; JPO; DERWENT; IBM_TDB) (see search history printout)	08/09/2007	EBK
www.google.com (see search history printouts)	08/09/2007	EBK
Updated EAST search (see search history printout)	02/01/2008	EBK
www.google.com (search terms: JTAG boundary scan)	02/01/2008	EBK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner